



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION
Generic Copy

30-MAR-2004

SUBJECT: ON Semiconductor Final Product/Process Change Notification #13388

TITLE: Addition of Tower Semiconductor Fab for Minigate(TM) Logic Products

EFFECTIVE DATE: 30-May-2004

AFFECTED CHANGE CATEGORY: Subcontractor Fab Site

AFFECTED PRODUCT DIVISION: Logic Products

ADDITIONAL RELIABILITY DATA: Available
Contact your local ON Semiconductor Sales Representative or
Ken Fergus <RRST50@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Representative
or Nilda Lopez <R39140@onsemi.com>

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:
Contact Sales Representative or Nilda Lopez <R39140@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 60 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

DESCRIPTION AND PURPOSE:

ON Semiconductor is pleased to announce expanded wafer capacity for MiniGate(TM) Logic products utilizing Tower Semiconductor. ON Semiconductor will implement this increase in capacity to support rapidly growing demand for these Logic products in an effort to assure our customers of ON Semiconductor's continued commitment to assured supply, on time delivery and continuous quality improvement.

The products will be redesigned using Tower Semiconductor's 0.6um design rules for their double layer metal, single polysilicon gate standard CMOS process. No performance changes are expected for the MiniGate(TM) products. All product performance will meet the current datasheet specifications.

Tower Semiconductor is a high volume Silicon supplier for flash memory, image sensors, mixed signal and standard CMOS products. They are located in Migdal Haemek, Israel, and are an ISO9001/QS9000 certified facility.

**Final Product/Process Change Notification #13388****RELIABILITY DATA SUMMARY:**

Reliability Test Results:

SC88A package, 1 lot ea. of 74VHC1GT00, 74VHC1G00, 74VHC1GT08:

Test	Conditions	Results (#fail/total SS)
High Temp Op Life	TA=150C for 504hrs	0/77, 0/77, 0/77
High Temp Bake	150C for 504 hrs	0/77, 0/77, 0/77
RSH	260C, 10 seconds	0/30, 0/30, 0/30
PC-Temp Cycle	-65/+150C for 500 cyc	0/77, 0/77, 0/77
PC-Autoclave	121C/100%RH/15psig for 96hrs	0/77, 0/77, 0/77
PC-HAST	131C/80%RH for 96 hrs	0/77, 0/77, 0/77
PC	168hrs 85C/85%, 3 IR at 260C	0/231, 0/231, 0/231

ELECTRICAL CHARACTERISTIC SUMMARY:

All product performance meets current datasheet specifications.

Data is available upon request.

CHANGED PART IDENTIFICATION:

Devices shipped after WW21 2004 may come from either site.

AFFECTED DEVICE LIST (WITHOUT SPECIALS):**PART**

M74VHC1GT126DF1G
MC74VHC1G09DFT1
MC74VHC1G09DFT1G
MC74VHC1G09DFT2
MC74VHC1G09DTT1
MC74VHC1G126DFT1
MC74VHC1G126DFT2
MC74VHC1G126DTT1
MC74VHC1G135DFT1
MC74VHC1G135DFT2
MC74VHC1G135DTT1
MC74VHC1G86DFT1
MC74VHC1G86DFT1G
MC74VHC1G86DFT2
MC74VHC1G86DFT2G
MC74VHC1G86DTT1
MC74VHC1GT126DF1
MC74VHC1GT126DF2
MC74VHC1GT126DT1
MC74VHC1GT86DFT1
MC74VHC1GT86DFT2
MC74VHC1GT86DTT1
NL17SZ04DFT2
NL17SZ04DFT2G
NL17SZ14DFT2
NL17SZ14DFT2G
NL17SZ16DFT2
NLVVHC1G86DFT2
NLVVHC1GT126DF1
NLVVHC1GT126DF2